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PCN # 251
Notification Date:
June 17, 2024

Product / Process Change Notice

Part Affected:

All Small Signal transistors manufactured in the SOT-23 case.

Extent of Change:

Additional assembly location and change in lead frame material; from Alloy42 to Copper CAC5.

Reason for Change:

As part of Central Semiconductor's supply chain risk mitigation initiative, and in an effort to ensure an undisrupted supply of product, an additional assembly location is being added for the referenced product. Device specifications, quality, and reliability are not impacted by this addition.

Effect of Change:

This addition does not affect the fit, form or function of the device.

Effective Date of Change:

July 15, 2024

Sample Availability:

Please contact your salesperson or manufacturer's representative for samples.



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Qualification:

No.	Test	Conditions (Reference standards are in bold)	Qty	Pass/ Fail	Test Results
1	Device Life Tests				
A	High Temperature Reverse Bias (HTRB)	T=125°C, t = 1000 hours Bias Conditions per Device Datasheet JESD22-A108	77	Pass	77/77
B	High Temperature Storage Life (HTSL)	T=150°C, t = 1000 hours JESD22-A103	77	Pass	77/77
C	Thermal Shock	100 cycles, dwell time = 5 min, -65°C to +150°C, max transfer time = 20s JESD22-A106	77	Pass	77/77
D	Temperature Cycling (TC)	-65°C to +150°C, T _{dwell} = 15min, 1000 cycles MIL-STD-750 TM1051	77	Pass	77/77
E	Resistance To Solder Shock	Pb free: T =270°C ±5°C, Dwell=7s +2/-0 SMDs fully submerge JESD22-A111	5	Pass	5/5
F	Solderability	Steam Age: T=93°C +3/-5°C. Pb-free Dip: T=245°C +/-5°C, Dwell time = 5+/-0.5sec MIL-STD-750 TM2026	15	Pass	15/15
G	Unbiased Highly Accelerated Temperature and Humidity Stress Test (UHAIST)	T = 130°C, RH = 85%, t = 96 hrs or T = 110°C, RH = 85%, t = 264 hrs as per JESD22-A110	77	Pass	77/77
H	Highly Accelerated Temperature and Humidity Stress Test (HAST)	T = 130°C, RH = 85%, t = 96 hrs or T = 110°C, RH = 85%, t = 264 hrs as per JESD22-A110 or T = 85°C, RH = 85%, t = 1000 hrs as per JESD22-A101 . Bias conditions per device datasheet.	77	Pass	77/77



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As per JEDEC standard JESD46, Customer Notification of Product/Process Changes by Solid-State Suppliers, a lack of acknowledgement of a PCN within thirty (30) days constitutes acceptance of the change.

The undersigned acknowledges and accepts Central Semiconductor's Product/Process Change Notification (PCN).

Company Name:	
Address:	
Printed Name:	
Title:	
Signature:	
Date:	